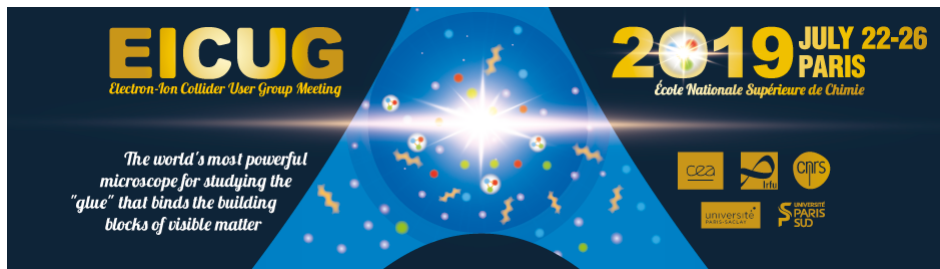


2019 EIC User Group Meeting



ID de Contribution: 12

Type: **Poster**

JLEIC Compton Polarimeter

lundi 22 juillet 2019 19:30 (15 minutes)

While Compton Polarimetry has been successfully used for electron polarimetry at several facilities already, some parameters need to be carefully taken into account to be able to handle the large beam current available at an EIC.

I will present a preliminary design for the Compton Polarimeter currently focusing on detecting the scattered electron in the case of the JLEIC machine.

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Classification de Session: Poster session

Classification de thématique: Detector R&D